# +5V, 1Msps, 4 \& 8-Channel, 8-Bit ADCs with 1 1 A Power-Down 

$\qquad$
General Description
The MAX114/MAX118 are microprocessor-compatible, 8 -bit, 4 -channel and 8 -channel analog-to-digital converters (ADCs). They operate from a single +5 V supply and use a half-flash technique to achieve a 660 ns conversion time (1Msps). A power-down (PWRDN) pin reduces current consumption typically to $1 \mu \mathrm{~A}$. The devices return from power-down mode to normal operating mode in less than 200 ns , allowing large supplycurrent reductions in burst-mode applications (in burst mode, the ADC wakes up from a low-power state at specified intervals to sample the analog input signals). Both converters include a track/hold, enabling the ADC to digitize fast analog signals.
Microprocessor ( $\mu \mathrm{P}$ ) interfaces are simplified because the ADC can appear as a memory location or I/O port without external interface logic. The data outputs use latched, three-state buffer circuitry for direct connection to an 8-bit parallel $\mu \mathrm{P}$ data bus or system input port. The MAX114/MAX118 input/reference configuration enables ratiometric operation.
The 4-channel MAX114 is available in a 24 -pin DIP or SSOP. The 8 -channel MAX118 is available in a 28 -pin DIP or SSOP. For +3 V applications, refer to the MAX113/MAX117 data sheet.

Applications
High-Speed DSP
Remote Data Acquisition
Communications Systems
Single +5V Supply Operation
Features
4 (MAX114) or 8 (MAX118) Analog Input Channels
Low Power: 40 mW (operating mode)
5 $\mu \mathrm{W}$ (power-down mode)
Total Unadjusted Error $\leq 1$ LSB
Fast Conversion Time: 660 ns per Channel
No External Clock Required

- Internal Track/Hold
1MHz Full-Power Bandwidth
Internally Connected 8th Channel Monitors
Reference Voltage (MAX118)

Ordering Information

| PART | TEMP. RANGE | PIN-PACKAGE |
| :--- | ---: | :--- |
| MAX114CNG | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 24 Narrow Plastic DIP |
| MAX114CAG | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 24 SSOP |
| MAX114C/D | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | Dice ${ }^{\star}$ |
| MAX114ENG | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 24 Narrow Plastic DIP |
| MAX114EAG | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 24 SSOP |
| MAX114MRG | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | 24 Narrow CERDIP ${ }^{* *}$ |

Ordering Information continued on last page.
*Dice are specified at $T_{A}=+25^{\circ} \mathrm{C}, D C$ parameters only.
**Contact factory for availability.
Pin Configurations appear on last page.
Functional Diagram


MAXIM

# +5V, 1Msps, 4 \& 8-Channel, 8-Bit ADCs with 1 $\boldsymbol{1}$ A Power-Down 

## ABSOLUTE MAXIMUM RATINGS

VDD to GND $\qquad$
Digital Out Votage
Voltage to GND -0.3 V to ( $\mathrm{V} D \mathrm{D}+0.3 \mathrm{~V}$ )
-0.3 V to (VDD + 0.3V)
-0.3 V to ( $\mathrm{V} D \mathrm{D}+0.3 \mathrm{~V}$ )
0.3 V to ( $\mathrm{V} D \mathrm{D}+0.3 \mathrm{~V}$ )

REF- to GND $\qquad$
IN_to GND $\qquad$
( $\mathrm{T}_{\mathrm{A}}=+70^{\circ} \mathrm{C}$ )
24-Pin Narrow Plastic DIP
(derate $13.33 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$ above $+70^{\circ} \mathrm{C}$ ) $\qquad$ 1.08 W 24-Pin SSOP (derate $8.00 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$ above $+70^{\circ} \mathrm{C}$ ) ................. 640 mW 24-Pin Narrow CERDIP (derate $12.50 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$ above $+70^{\circ} \mathrm{C}$ ) $\qquad$ 1W

28-Pin Wide Plastic DIP
(derate $14.29 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$ above $+70^{\circ} \mathrm{C}$ )................................... 1.14 W 28-Pin SSOP (derate $9.52 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$ above $+70^{\circ} \mathrm{C}$ ).............. 762 mW 28-Pin Wide CERDIP
(derate $16.67 \mathrm{~mW} /{ }^{\circ} \mathrm{C}$ above $+70^{\circ} \mathrm{C}$ )....................................1.33W
Operating Temperature Ranges
MAX114/MAX118C__....................................... $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$
MAX114/MAX118E
MAX114/MAX118M__.................................... $55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$
Storage Temperature Range ............................. $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
Lead Temperature (soldering, 10sec) ............................. $+300^{\circ} \mathrm{C}$

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## ELECTRICAL CHARACTERISTICS

( $\mathrm{V} D \mathrm{DD}=+5 \mathrm{~V} \pm 5 \%$, REF+ = 5V, REF- = GND, Read Mode (MODE $=\mathrm{GND}$ ), $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{MIN}}$ to $\mathrm{T}_{\mathrm{MAX}}$, unless otherwise noted.)

| PARAMETER | SYMBOL | CONDITIONS | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| ACCURACY (Note 1) |  |  |  |  |  |  |
| Resolution | N |  | 8 |  |  | Bits |
| Total Unadjusted Error | TUE |  |  |  | $\pm 1$ | LSB |
| Differential Nonlinearity | DNL | No-missing-codes guaranteed |  |  | $\pm 1$ | LSB |
| Zero-Code Error |  |  |  |  | $\pm 1$ | LSB |
| Full-Scale Error |  |  |  |  | $\pm 1$ | LSB |
| Channel-to-Channel Mismatch |  |  |  |  | $\pm 1 / 4$ | LSB |
| DYNAMIC PERFORMANCE |  |  |  |  |  |  |
| Signal-to-Noise Plus Distortion Ratio | SINAD | MAX11_C/E, fSAMPLE $=1 \mathrm{MHz}$, $\mathrm{fIN}_{-}=195.8 \mathrm{kHz}$ | 45 |  |  | dB |
|  |  | MAX11_M, fSAMPLE $=740 \mathrm{kHz}$, $\mathrm{fIN}=195.7 \mathrm{kHz}$ | 45 |  |  |  |
| Total Harmonic Distortion | THD | MAX11_C/E, fSAMPLE $=1 \mathrm{MHz}$, $\mathrm{fIN}=195.8 \mathrm{kHz}$ |  |  | -50 | dB |
|  |  | MAX11_M, fSAMPLE $=740 \mathrm{kHz}$, $\mathrm{fIN}=195.7 \mathrm{kHz}$ |  |  | -50 |  |
| Spurious-Free Dynamic Range | SFDR | MAX11_C/E, fSAMPLE $=1 \mathrm{MHz}, \mathrm{fIN}_{-}=195.8 \mathrm{kHz}$ | 50 |  |  | dB |
|  |  | MAX11_M, fSAMPLE $=740 \mathrm{kHz}$, $\mathrm{fIN}_{-}=195.7 \mathrm{kHz}$ | 50 |  |  |  |
| Input Full-Power Bandwidth |  | $\mathrm{VIN}_{\text {_ }}=5 \mathrm{Vp}-\mathrm{p}$ |  | 1 |  | MHz |
| Input Slew Rate, Tracking |  |  | 3.1 | 15 |  | V/ $\mu \mathrm{s}$ |
| ANALOG INPUT |  |  |  |  |  |  |
| Input Voltage Range | $\mathrm{V}_{1} \mathrm{~N}_{-}$ |  | VREF- |  | $\mathrm{V}_{\text {REF }+}$ | V |
| Input Leakage Current | IIN_ | GND < VIN_ < V ${ }_{\text {DD }}$ |  |  | $\pm 3$ | $\mu \mathrm{A}$ |
| Input Capacitance | $\mathrm{ClN}_{-}$ |  |  | 32 |  | pF |
| REFERENCE INPUT |  |  |  |  |  |  |
| Reference Resistance | RREF |  | 1 | 2 | 4 | $\mathrm{k} \Omega$ |
| REF+ Input Voltage Range |  |  | VREF- |  | VDD | V |
| REF- Input Voltage Range |  |  | GND |  | VREF+ | V |

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## ELECTRICAL CHARACTERISTICS (continued)

( $\mathrm{V}_{\mathrm{DD}}=+5 \mathrm{~V} \pm 5 \%$, REF $+=5 \mathrm{~V}$, REF- $=$ GND, Read Mode (MODE $=G N D$ ), $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{\mathrm{MIN}}$ to $\mathrm{T}_{\mathrm{MAX}}$, unless otherwise noted.)

| PARAMETER | SYMBOL | CONDITIONS |  | MIN | TYP | MAX | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| LOGIC INPUTS |  |  |  |  |  |  |  |
| Input High Voltage | Vinh | $\overline{\mathrm{CS}}, \overline{\mathrm{WR}}, \overline{\mathrm{RD}}, \overline{\mathrm{PW}} \mathrm{RDN}, \mathrm{A} 0, \mathrm{~A} 1, \mathrm{~A} 2$ |  | 2.4 |  |  | V |
|  |  | MODE |  | 3.5 |  |  |  |
| Input Low Voltage | VINL | $\overline{\mathrm{CS}}, \overline{\mathrm{WR}}, \overline{\mathrm{RD}}, \overline{\mathrm{PW} R \mathrm{DN}}, \mathrm{A} 0, \mathrm{~A} 1, \mathrm{~A} 2$ |  | 1.5 |  |  | V |
|  |  | MODE |  |  |  |  |  |
| Input High Current | IINH | $\overline{\mathrm{CS}}, \overline{\mathrm{RD}}, \overline{\mathrm{PWRDN}}, \mathrm{A}, \mathrm{A} 1, \mathrm{~A} 2$ |  |  |  | $\pm 1$ | $\mu \mathrm{A}$ |
|  |  | $\overline{\mathrm{WR}}$ |  |  | $\pm 3$ |  |  |
|  |  | MODE |  |  | 50 | 200 |  |
| Input Low Current | IINL | $\overline{\overline{C S}}, \overline{\mathrm{WR}}, \overline{\mathrm{RD}}, \overline{\text { PWRDN, }}$, MODE, A0, A1, A2 |  |  | $\pm 1$ |  | $\mu \mathrm{A}$ |
| Input Capacitance (Note 2) | CIN | $\overline{\mathrm{CS}}, \overline{\mathrm{WR}}, \overline{\mathrm{RD}}, \overline{\mathrm{PWRDN}}, \mathrm{MODE}, \mathrm{A}, \mathrm{A} 1, \mathrm{~A} 2$ |  |  | 5 | 8 | pF |
| LOGIC OUTPUTS |  |  |  |  |  |  |  |
| Output Low Voltage | VoL | ISINK $=1.6 \mathrm{~mA}$, $\overline{\mathrm{INT}}, \mathrm{D} 0-\mathrm{D} 7$ |  |  | 0.4 |  | V |
|  |  | RDY, ISINK $=2.6 \mathrm{~mA}$ |  |  |  |  |  |
| Output High Voltage | VOH | ISOURCE $=360 \mu \mathrm{~A}$, INT, D0-D7 |  | 4 |  |  | V |
| Three-State Current | ILKG | D0-D7, RDY, digital outputs = 0V to VDD |  |  | $\pm 3$ |  | $\mu \mathrm{A}$ |
| Three-State Capacitance (Note 2) | Cout | D0-D7, RDY |  |  | 5 | 8 | pF |
| POWER REQUIREMENTS |  |  |  |  |  |  |  |
| Supply Voltage | VDD |  |  | 4.75 |  | 5.25 | V |
| VDD Supply Current | IDD | $\begin{aligned} & \overline{\mathrm{CS}}=\overline{\mathrm{RD}}=0 \mathrm{~V}, \\ & \overline{\mathrm{PWRDN}}=\mathrm{VDD} \end{aligned}$ | MAX11_C |  | 8 | 15 | mA |
|  |  |  | MAX11_E/M |  | 8 | 20 |  |
| Power-Down VDd Current |  | $\overline{\mathrm{CS}}=\overline{\mathrm{RD}}=\mathrm{V}_{\mathrm{DD}}, \overline{\mathrm{PWRRN}}=0 \mathrm{~V}($ Note 3) |  |  | 1 | 10 | $\mu \mathrm{A}$ |
| Power-Supply Rejection | PSR | $\mathrm{V}_{\mathrm{DD}}=4.75 \mathrm{~V}$ to | $\mathrm{V}_{\mathrm{DD}}=4.75 \mathrm{~V}$ to $5.25 \mathrm{~V}, \mathrm{VREF}=4.75 \mathrm{~V}$ |  | $\pm 1 / 16$ | $\pm 1 / 4$ | LSB |

Note 2: Guaranteed by design.
Note 3: Power-down current increases if logic inputs are not driven to GND or VDD.

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## TIMING CHARACTERISTICS

(VDD $=+4.75 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$, unless otherwise noted.) (Note 4)

| PARAMETER | SYMBOL | CONDITIONS |  | $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ <br> ALL GRADES |  |  | $\mathrm{T}_{\mathrm{A}}=\mathrm{T}_{\text {MIN }}$ to $\mathrm{T}_{\text {MAX }}$ |  |  |  | UNITS |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  | MAX11_C/E | MAX11_M |  |  |
|  |  |  |  | MIN | TYP | MAX | MIN | MAX | MIN | MAX |  |
| Conversion Time (WR-RD Mode) | tcwr | $\begin{aligned} & \text { trD < tiNTL, } \\ & (\text { Note 5) } \end{aligned}$ | $\mathrm{CL}_{\mathrm{L}}=20 \mathrm{pF}$ |  |  |  |  |  | 660 |  |  |  |  | ns |
|  |  |  | $C_{L}=100 \mathrm{pF}$ |  |  | 685 |  | 865 |  | 1125 |  |  |
| Conversion Time (RD Mode) | tcri |  |  |  |  | 700 |  | 875 |  | 975 | ns |  |
| Power-Up Time | tup |  |  |  |  | 320 |  | 370 |  | 520 | ns |  |
| $\overline{\mathrm{CS}}$ to $\overline{\mathrm{RD}}, \overline{\mathrm{WR}}$ Setup Time | tcss |  |  | 0 |  |  | 0 |  | 0 |  | ns |  |
| $\overline{\mathrm{CS}}$ to $\overline{\mathrm{RD}}, \overline{\mathrm{WR}}$ Hold Time | tCSH |  |  | 0 |  |  | 0 |  | 0 |  | ns |  |
| $\overline{\mathrm{CS}}$ to RDY Delay | trdy | $\begin{aligned} & C_{L}=50 \mathrm{pF}, \\ & R_{\mathrm{L}}=5.1 \mathrm{k} \Omega \end{aligned}$ |  |  |  | 70 |  | 85 |  | 100 | ns |  |
| Data-Access Time (RD Mode) | tacco | $C_{L}=100 \mathrm{pF}$ | ote 5) |  |  | $\begin{gathered} \mathrm{t} C R D+ \\ 50 \end{gathered}$ |  | $\begin{gathered} \mathrm{t} \mathrm{CRD}+ \\ 65 \end{gathered}$ |  | $\begin{gathered} \text { tCRD } \\ 75 \end{gathered}$ | ns |  |
| $\overline{\mathrm{RD}}$ to $\overline{\mathrm{INT}}$ Delay (RD Mode) | tinth | $C \mathrm{~L}=50 \mathrm{pF}$ |  |  | 50 | 80 |  | 85 |  | 90 | ns |  |
| Data Hold Time | tDH | (Note 6) |  |  |  | 60 |  | 70 |  | 80 | ns |  |
| Minimum Acquisition Time | tACQ | (Note 7) |  | 160 |  |  | 185 |  | 260 |  | ns |  |
| $\overline{\text { WR Pulse Width }}$ | tWR |  |  | 0.25 |  | 10 | 0.28 | 10 | 0.4 | 10 | $\mu \mathrm{s}$ |  |
| Delay Between $\overline{W R}$ and RD Pulses | tRD |  |  | 0.25 |  |  | 0.35 |  | 0.45 |  | $\mu \mathrm{s}$ |  |
| $\overline{\mathrm{RD}}$ Pulse Width (WR-RD Mode) | tREAD1 | tRD < tINTL, determined | tACC1 | 160 |  |  | 205 |  | 240 |  | ns |  |
| Data-Access Time (WR-RD Mode) | $\mathrm{taCC}^{\text {a }}$ | $\mathrm{t}_{\mathrm{RD}}<\mathrm{t} \text { INTL, }$ <br> (Note 5) | $=100 \mathrm{pF}$ |  |  | 185 |  | 235 |  | 275 | ns |  |
| $\overline{\mathrm{RD}}$ to INT Delay | tRI |  |  |  |  | 150 |  | 185 |  | 220 | ns |  |
| $\overline{\text { WR }}$ to INT Delay | tINTL | $\mathrm{CL}_{\mathrm{L}}=50 \mathrm{pF}$ |  |  | 380 | 500 |  | 610 |  | 700 | ns |  |
| $\overline{R D}$ Pulse Width (WR-RD Mode) | tread2 | $\begin{aligned} & \text { trD }>\mathrm{t}_{\mathrm{I} N \mathrm{NLL}}, \\ & \mathrm{t}_{\mathrm{ACC}} \\ & \hline \end{aligned}$ | termined by | 65 |  |  | 75 |  | 85 |  | ns |  |
| Data-Access Time (WR-RD Mode) | $\mathrm{taCC}^{2}$ | $\begin{aligned} & \text { trD > tiNTL, } \\ & \text { (Note 5) } \end{aligned}$ | $=100 \mathrm{pF}$ |  |  | 90 |  | 110 |  | 130 | ns |  |
| $\overline{\text { WR }}$ to INT Delay | tIHWR | Pipelined mo | e, $C_{L}=50 \mathrm{pF}$ |  |  | 80 |  | 100 |  | 120 | ns |  |
| Data-Access Time after $\overline{\text { INT }}$ | tID | Pipelined mo | e, $C_{L}=100 \mathrm{pF}$ |  |  | 45 |  | 60 |  | 70 | ns |  |
| Multiplexer Address Hold Time | $\mathrm{t}_{\text {AH }}$ |  |  | 30 |  |  | 35 |  | 40 |  | ns |  |

Note 4: Input control signals are specified with $\mathrm{t}_{\mathrm{r}}=\mathrm{t}_{\mathrm{f}}=5 \mathrm{~ns}, 10 \%$ to $90 \%$ of 5 V , and timed from a voltage level of 1.6 V .
Note 5: See Figure 1 for load circuit. Parameter defined as the time required for the output to cross 0.8 V or 2.4 V .
Note 6: See Figure 2 for load circuit. Parameter defined as the time required for the data lines to change 0.5 V .
Note 7: Also defined as the Minimum Address-Valid to Convert-Start Time.

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## $\left(\mathrm{V}_{\mathrm{DD}}=+5 \mathrm{~V}, \mathrm{~T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}\right.$, unless otherwise noted. $)$

Typical Operating Characteristics


MAX114/MAX118





## +5V, 1Msps, 4 \& 8-Channel, 8-Bit ADCs with 1 1 A Power-Down

| PIN |  | NAME | FUNCTION |
| :---: | :---: | :---: | :---: |
| MAX114 | MAX118 |  |  |
| - | 1 | IN6 | Analog Input Channel 6 |
| - | 2 | IN5 | Analog Input Channel 5 |
| 1 | 3 | IN4 | Analog Input Channel 4 |
| 2 | 4 | IN3 | Analog Input Channel 3 |
| 3 | 5 | IN2 | Analog Input Channel 2 |
| 4 | 6 | IN1 | Analog Input Channel 1 |
| 5 | 7 | MODE | Mode Selection Input. Internally pulled low with a $50 \mu \mathrm{~A}$ current source. MODE $=0$ activates read mode; MODE = 1 activates write-read mode (see Digital Interface Section). |
| 6 | 8 | D0 | Three-State Data Output (LSB) |
| 7, 8, 9 | 9, 10, 11 | D1, D2, D3 | Three-State Data Outputs |
| 10 | 12 | $\overline{\mathrm{RD}}$ | Read Input. $\overline{\mathrm{RD}}$ must be low to access data (see Digital Interface section). |
| 11 | 13 | $\overline{\text { INT }}$ | Interrupt Output. INT goes low to indicate end of conversion (see Digital Interface section). |
| 12 | 14 | GND | Ground |
| 13 | 15 | REF- | Lower Limit of Reference Span. REF- sets the zero-code voltage. Range is GND $\leq$ $\mathrm{V}_{\text {REF }}$ - $\mathrm{V}_{\text {REF }}$. |
| 14 | 16 | REF+ | Upper Limit of Reference Span. REF+ sets the full-scale input voltage. Range is VREF$<\mathrm{V}_{\mathrm{REF}}^{+} \mathrm{\leq}$ VDD. Internally hard-wired to IN8 (Table 1). |
| 15 | 17 | $\overline{\text { WR/RDY }}$ | Write-Control Input/Ready-Status Output (see Digital Interface section) |
| 16 | 18 | $\overline{\mathrm{CS}}$ | Chip-Select Input. $\overline{\mathrm{CS}}$ must be low for the device to recognize $\overline{\mathrm{WR}}$ or $\overline{\mathrm{RD}}$ inputs. |
| 17, 18, 19 | 19, 20, 21 | D4, D5, D6 | Three-State Data Outputs |
| 20 | 22 | D7 | Three-State Data Output (MSB) |
| - | 23 | A2 | Multiplexer Channel Address Input (MSB) |
| 21 | 24 | A1 | Multiplexer Channel Address Input |
| 22 | 25 | A0 | Multiplexer Channel Address Input (LSB) |
| 23 | 26 | $\overline{\text { PWRDN }}$ | Power-Down Input. $\overline{\text { PWRDN }}$ reduces supply current when low. |
| 24 | 27 | VDD | Positive Supply, +5V |
| - | 28 | IN7 | Analog Input Channel 7 |

# +5V, 1Msps, 4 \& 8-Channel, 8-Bit ADCs with 1 1 A Power-Down 

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## Detailed Description

Converter Operation
The MAX114/MAX118 use a half-flash conversion technique (see Functional Diagram) in which two 4-bit flash ADC sections achieve an 8 -bit result. Using 15 comparators, the flash ADC compares the unknown input voltage to the reference ladder and provides the upper four data bits. An internal digital-to-analog converter (DAC) uses the four most significant bits (MSBs) to generate both the analog result from the first flash conversion and a residue voltage that is the difference between the unknown input and the DAC voltage. The residue is then compared again with the flash comparators to obtain the lower four data bits (LSBs).
An internal analog multiplexer enables the devices to read four (MAX114) or eight (MAX118) different analog voltages under microprocessor ( $\mu \mathrm{P}$ ) control. One of the MAX118's analog channels, IN8, is internally hardwired and always reads VREF+ when selected.


Figure 1. Load Circuits for Data-Access Time Test


Figure 2. Load Circuits for Data-Hold Time Test


#### Abstract

Power-Down Mode In burst-mode or low sample-rate applications, the MAX114/MAX118 can be shut down between conversions, reducing supply current to microamp levels (see Typical Operating Characteristics). A logic low on the PWRDN pin shuts the devices down, reducing supply current typically to $1 \mu \mathrm{~A}$ when powered from a single +5 V supply. A logic high on PWRDN wakes up the MAX114/MAX118, and the selected analog input enters the track mode. The signal is fully acquired after 360 ns (this includes both the power-up delay and the track/hold acquisition time), and a new conversion can be started. If the power-down feature is not required, connect $\overline{\text { PWRDN }}$ to VDD. For minimum current consumption, keep digital inputs at the supply rails in power-down mode. Refer to the Reference section for information on reducing reference current during power-down.


Digital Interface
The MAX114/MAX118 have two basic interface modes, which are set by the MODE pin. When MODE is low, the converters are in read mode; when MODE is high, the converters are set up for write-read mode. The AO, A1, and A2 inputs control channel selection, as shown in Table 1. The address must be valid for a minimum time, tACQ, before the next conversion starts.

Table 1. Truth Table for Input Channel Selection

| MAX114 |  | MAX118 |  |  | SELECTED CHANNEL |
| :---: | :---: | :---: | :---: | :---: | :---: |
| A1 | A0 | A2 | A1 | A0 |  |
| 0 | 0 | 0 | 0 | 0 | IN1 |
| 0 | 1 | 0 | 0 | 1 | IN2 |
| 1 | 0 | 0 | 1 | 0 | IN3 |
| 1 | 1 | 0 | 1 | 1 | IN4 |
| - | - | 1 | 0 | 0 | IN5 |
| - | - | 1 | 0 | 1 | IN6 |
| - | - | 1 | 1 | 0 | IN7 |
| - | - | 1 | 1 | 1 | IN8 |

Read Mode (MODE $=0$ )
In read mode, conversions and data access are controlled by the $\overline{R D}$ input (Figure 3). The comparator inputs track the analog input voltage for the duration of tACQ. Initiate a conversion by driving $\overline{\mathrm{CS}}$ and $\overline{\mathrm{RD}}$ low. With $\mu$ Ps that can be forced into a wait state, hold RD low until output data appears. The $\mu \mathrm{P}$ starts the conversion, waits, and then reads data with a single read instruction.

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In read mode, $\overline{W R} / R D Y$ is configured as a status output (RDY), so it can drive the ready or wait input of a $\mu \mathrm{P}$. RDY is an open-collector output (no internal pull-up) that goes low after the falling edge of $\overline{C S}$ and goes high at the end of the conversion. If not used, the WR/RDY pin can be left unconnected. The INT output goes low at the end of the conversion and returns high on the rising edge of $\overline{\mathrm{CS}}$ or $\overline{\mathrm{RD}}$.

Write-Read Mode (MODE =1)
Figures 4 and 5 show the operating sequence for writeread mode. The comparator inputs track the analog input voltage for the duration of $\operatorname{tACQ}$. The conversion is initiated by a falling edge of WR. When WR returns high, the result of the four-MSBs flash is latched into the output buffers and the conversion of the four-LSBs flash starts. INT goes low, indicating conversion end, and the lower four data bits are latched into the output buffers. The data is then accessible after $\overline{\mathrm{RD}}$ goes low (see Timing Characteristics).
A minimum acquisition time ( $\mathrm{t} A C Q$ ) is required from $\overline{\mathrm{NT}}$ going low to the start of another conversion (WR going low).
Options for reading data from the converter include using internal delay, reading before delay, and pipelined operation (discussed in the following sections).

Using Internal Delay
The $\mu \mathrm{P}$ waits for the $\overline{\mathrm{NT}}$ output to go low before reading the data (Figure 4). INT goes low after the rising edge of $\overline{W R}$, indicating that the conversion is complete and the result is available in the output latch. With $\overline{C S}$ low, data outputs D0-D7 can be accessed by pulling RD low. INT is then reset by the rising edge of $\overline{\mathrm{CS}}$ or $\overline{\mathrm{RD}}$.


Figure 3. Read Mode Timing $(M O D E=0)$

## Fastest Conversion: Reading Before Delay

Figure 5 shows an external method of controlling the conversion time. The internally generated delay (tINTL) varies slightly with temperature and supply voltage, and can be overridden with $\overline{\mathrm{RD}}$ to achieve the fastest conversion time. $\overline{\mathrm{RD}}$ is brought low after the rising edge of WR, but before INT goes low. This completes the conversion and enables the output buffers that contain the conversion result (D0-D7). INT also goes low after the falling edge of $\overline{R D}$ and is reset on the rising edge of $\overline{\mathrm{RD}}$ or $\overline{\mathrm{CS}}$. The total conversion time is therefore: twR + $t_{\text {RD }}+\mathrm{t}_{\mathrm{ACC}}=660 \mathrm{~ns}$.


Figure 4. Write-Read Mode Timing $\left(t_{R D}>t_{I N T L}\right)(M O D E=1)$


Figure 5. Write-Read Mode Timing (tRD $\left.<t_{\text {INTL }}\right)(M O D E=1)$

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## Pipelined Operation

Besides the two standard write-read-mode options, pipelined operation can be achieved by connecting $\overline{\mathrm{WR}}$ to $\overline{\mathrm{RD}}$ (Figure 6). With $\overline{\mathrm{CS}}$ low, driving $\overline{\mathrm{WR}}$ and $\overline{\mathrm{RD}}$ low initiates a conversion and concurrently reads the result of the previous conversion.

## Analog Considerations

## Reference

Figures 7a, 7b, and 7c show typical reference connections. The voltages at REF+ and REF- set the ADC's analog input range (see Figure 10). The voltage at REFdefines the input that produces an output code of all zeros, and the voltage at REF+ defines the input that produces an output code of all ones.
The internal resistance from REF+ to REF- can be as low as $1 \mathrm{k} \Omega$, and current will flow through it even when the MAX114/MAX118 are shut down. Figure 7d shows how an N-channel MOSFET can be connected to REF-


Figure 7a. Power Supply as Reference


Figure 7b. External Reference, 4.096V Full Scale


Figure 6. Pipelined Mode Timing $(\overline{W R}=\overline{R D})(M O D E=1)$


Figure 7c. Input Not Referenced to GND


Figure 7d. An N-channel MOSFET switches off the reference load during power-down

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to break this current path during power-down. The FET should have an on-resistance of less than $2 \Omega$ with a 5 V gate drive. When REF- is switched, as in Figure 7d, a new conversion can be initiated after waiting a period of time equal to the power-up delay (tup) plus the N channel FET's turn-on time.
Although REF+ is frequently connected to VDD, the circuit of Figure 7d uses a low-current, low-dropout, 4.096 V voltage reference: the MAX874. Since the MAX874 cannot continuously furnish enough current for the reference resistance, this circuit is intended for applications where the MAX114/MAX118 are normally in standby and are turned on in order to make measurements at intervals greater than $65 \mu \mathrm{~s}$. C1 (the capacitor connected to REF+) is slowly charged by the MAX874 during the standby period, and furnishes the reference current during the short measurement period.
C1's $3.3 \mu \mathrm{~F}$ value ensures a voltage drop of less than $1 / 2$ LSB when performing four to eight successive conversions. Larger capacitors reduce the error still further. Use ceramic or tantalum capacitors for C1.

Initial Power-Up
When power is first applied, perform a conversion to initialize the MAX114/MAX118. Disregard the output data.

## Bypassing

Use a $4.7 \mu \mathrm{~F}$ electrolytic in parallel with a $0.1 \mu \mathrm{~F}$ ceramic capacitor to bypass VDD to GND. Minimize capacitor lead lengths.
Bypass the reference inputs with $0.1 \mu \mathrm{~F}$ capacitors, as shown in Figures 7a, 7b, and 7c.

## Analog Inputs

Figure 8 shows the equivalent circuit of the MAX114/ MAX118 input. When a conversion starts and $\overline{W R}$ is low, VIN is connected to sixteen 0.6 pF capacitors. During this acquisition phase, the input capacitors charge to the input voltage through the resistance of the internal analog switches. In addition, about 22pF of stray capacitance must be charged. The input can be modeled as an equivalent RC network (Figure 9). As source impedance increases, the capacitors take longer to charge.
The typical 32 pF input capacitance allows source resistance as high as $800 \Omega$ without setup problems. For larger resistances, the acquisition time (tACQ) must be increased.
Internal protection diodes, which clamp the analog input to $V_{D D}$ and GND, allow the channel input pins to swing from GND -0.3 V to $\mathrm{VDD}_{\mathrm{D}}+0.3 \mathrm{~V}$ without damage. However, for accurate conversions near full scale, the inputs must not exceed VDD by more than 50 mV or be lower than GND by 50 mV .
If the analog input exceeds 50 mV beyond the supplies, limit the input current to no more than 2 mA , as excessive current will degrade the conversion accuracy of the on channel.

Track/Hold
The track/hold enters hold mode when a conversion starts ( $\overline{\mathrm{RD}}$ low or $\overline{\mathrm{WR}}$ low). INT goes low at the end of the conversion, at which point the track/hold enters track mode. The next conversion can start after the minimum acquisition time, tACQ.


Figure 9. RC Network Equivalent Input Model

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## Transfer Function

Figure 10 shows the MAX114/MAX118's nominal transfer function. Code transitions occur halfway between successive-integer LSB values. Output coding is binary with $1 \mathrm{LSB}=\left(\mathrm{VREF}_{+}-\mathrm{V}_{\text {REF }}\right) / 256$.

Conversion Rate
The maximum sampling rate (fMAX) for the MAX114/ MAX118 is achieved in write-read mode (tRD < tINTL), and is calculated as follows:

$$
\begin{aligned}
& \mathrm{f}_{\mathrm{MAX}}=\frac{1}{\mathrm{t}_{\mathrm{WR}}+\mathrm{t}_{\mathrm{RD}}+\mathrm{t}_{\mathrm{RI}}+\mathrm{t}_{\mathrm{ACQ}}} \\
& \mathrm{f}_{\mathrm{MAX}}=\frac{1}{250 \mathrm{~ns}+250 \mathrm{~ns}+150 \mathrm{~ns}+160 \mathrm{~ns}} \\
& \mathrm{f}_{\mathrm{MAX}}=1.23 \mathrm{MHz}
\end{aligned}
$$

where twR = the write pulse width, tRD = the delay between write and read pulses, $t_{\mathrm{RI}}=\overline{\mathrm{RD}}$ to $\overline{\mathrm{INT}}$ delay, and $\operatorname{tACQ}=$ minimum acquisition time .

## Signal-to-Noise Ratio and

 Effective Number of BitsSignal-to-noise plus distortion (SINAD) is the ratio of the fundamental input frequency's RMS amplitude to all other ADC output signals. The output spectrum is limited to frequencies above DC and below one-half the ADC sample rate.
The theoretical minimum analog-to-digital noise is caused by quantization error, and results directly from the ADC's resolution: $\mathrm{SNR}=(6.02 \mathrm{~N}+1.76) \mathrm{dB}$, where N is the number of bits of resolution. Therefore, a perfect 8-bit ADC can do no better than 50dB.
The FFT Plot (see Typical Operating Characteristics) shows the result of sampling a pure 195.8 kHz sinusoid at a 1 MHz rate. This FFT plot of the output shows the output level in various spectral bands.
The effective resolution (or "effective number of bits") the ADC provides can be measured by transposing the equation that converts resolution to SNR: $N=$ (SINAD 1.76) / 6.02 (see Typical Operating Characteristics).

Total Harmonic Distortion Total harmonic distortion (THD) is the ratio of the RMS sum of all harmonics of the input signal (in the frequency


Figure 10. Transfer Function
band above DC and below one-half the sample rate) to the fundamental itself. This is expressed as:

$$
\mathrm{THD}=20 \log \left[\frac{\sqrt{\mathrm{~V}_{2}^{2}+\mathrm{V}_{3}^{2}+\mathrm{V}_{4}^{2}+\ldots \mathrm{V}_{\mathrm{N}}{ }^{2}}}{\mathrm{~V}_{1}}\right]
$$

where $\mathrm{V}_{1}$ is the fundamental RMS amplitude, and $\mathrm{V}_{2}$ through $\mathrm{V}_{\mathrm{N}}$ are the amplitudes of the 2nd through Nth harmonics.

## Spurious-Free Dynamic Range

Spurious-free dynamic range (SFDR) is the ratio of the fundamental RMS amplitude to the amplitude of the next largest spectral component (in the frequency band above DC and below one-half the sample rate). Usually the next largest spectral component occurs at some harmonic of the input frequency. However, if the ADC is exceptionally linear, it may occur only at a random peak in the ADC's noise floor. See the Signal-toNoise Ratio graph in Typical Operating Characteristics.

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MAX114/MAX118

## _Ordering Information (continued)

$\qquad$ Chip Information

| PART | TEMP. RANGE | PIN-PACKAGE |
| :--- | :--- | :--- |
| MAX118CPI | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 28 Wide Plastic DIP |
| MAX118CAI | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | 28 SSOP |
| MAX118C/D | $0^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ | Dice ${ }^{*}$ |
| MAX118EPI | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 28 Wide Plastic DIP |
| MAX118EAI | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 28 SSOP |
| MAX118MJI | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ | 28 Wide CERDIP** |

TRANSISTOR COUNT: 2011
${ }^{*}$ Dice are specified at $T_{A}=+25^{\circ} \mathrm{C}, D C$ parameters only.
**Contact factory for availability.
Pin Configurations


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